

INTERNATIONAL STANDARD

NORME INTERNATIONALE

**Integrated circuits – Measurement of electromagnetic immunity –
Part 8: Measurement of radiated immunity – IC stripline method**

**Circuits intégrés – Mesure de l'immunité électromagnétique –
Partie 8: Mesure de l'immunité rayonnée – Méthode de la ligne TEM à plaques
pour circuit intégré**





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INTERNATIONAL ELECTROTECHNICAL COMMISSION

**INTEGRATED CIRCUITS –
MEASUREMENT OF ELECTROMAGNETIC IMMUNITY –**

**Part 8: Measurement of radiated immunity –
IC stripline method**

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47A/882/FDIS	47A/886/RVD

Full information on the voting for the approval of this standard can be found in the report on voting indicated in the above table.

This publication has been drafted in accordance with the ISO/IEC Directives, Part 2.

This part of IEC 62132 is to be read in conjunction with IEC 62132-1.

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